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Application/Control No.	Applicant(s)/Patent under Reexamination	
09/298,453	BAIN ET AL.	
Examiner	Art Unit	
Cong-Lac Huynh	2178	

SEARCHED				
Class	Subclass	Date	Examiner	
715	501.1	9/8/2005	CLH	
	500	9/8/2005	CLH	
	781	9/8/2005	CLH	
	,			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
715	501.1	9/8/2005	CLH
	500	9/8/2005	CLH
Interference Search History Printout		9/8/2005	CLH

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East (US-PGPUB, USPAT, EPO, JPO, Derwent)	9/8/2005	CLH
ACM .	9/8/2005	CLH
ProQuest	9/8/2005	CLH
IEEE	9/8/2005	CLH
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